

# Product Preview

## 8K x 9 Bit Static Random Access Memory

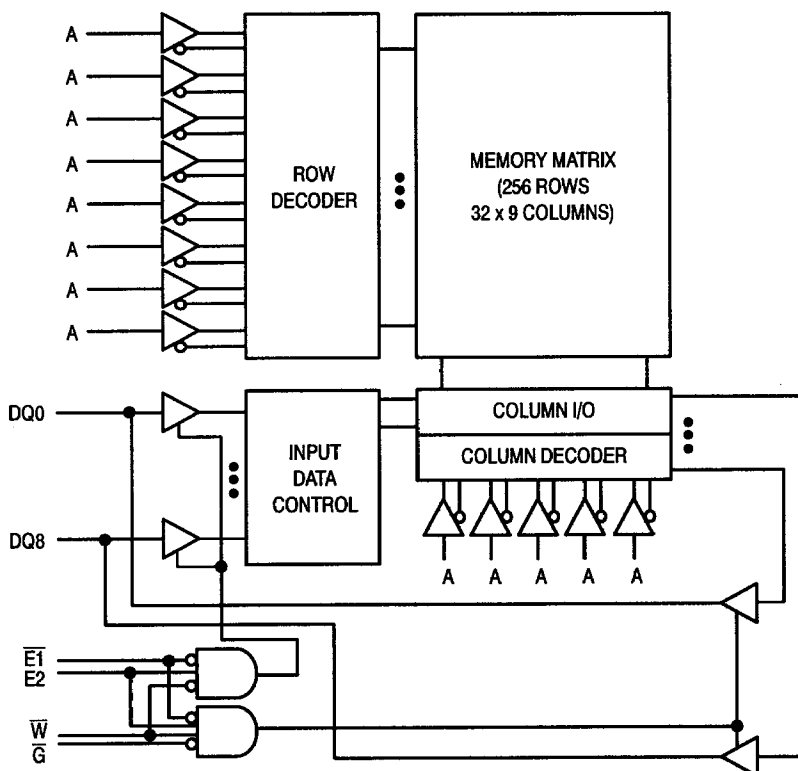
The MCM6765A is a 73,728 bit static random access memory organized as 8192 words of 9 bits, fabricated using high-performance silicon-gate BiCMOS technology. Static design eliminates the need for external clocks or timing strobes.

Output enable ( $\bar{G}$ ) is a special control feature that provides increased system flexibility and eliminates bus contention problems.

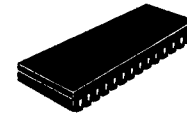
The MCM6765A is available in a 300 mil, 28 lead surface-mount SOJ package.

- Single 5 V  $\pm$  10% Power Supply
- Fully Static — No Clock or Timing Strokes Necessary
- All Inputs and Outputs are TTL Compatible
- Three State Outputs
- Fast Access Times:
  - MCM6765A-8 = 8 ns
  - MCM6765A-10 = 10 ns

### BLOCK DIAGRAM



## MCM6765A



**J PACKAGE**  
**300 MIL SOJ**  
**CASE 810B**

### PIN ASSIGNMENT

A8	1	28	VCC
A7	2	27	$\bar{W}$
A6	3	26	E2
A5	4	25	A9
A4	5	24	A10
A3	6	23	A11
A2	7	22	$\bar{G}$
A1	8	21	A12
A0	9	20	$\bar{E1}$
DQ0	10	19	DQ8
DQ1	11	18	DQ7
DQ2	12	17	DQ6
DQ3	13	16	DQ5
VSS	14	15	DQ4

### PIN NAMES

A0 – A12	Address Input
DQ0 – DQ8	Data Input/Output
$\bar{W}$	Write Enable
$\bar{G}$	Output Enable
$\bar{E1}$ , E2	Chip Enable
NC	No Connection
VCC	Power Supply (+5 V)
VSS	Ground

This document contains information on a new product. Motorola reserves the right to change or discontinue this product without notice.



**TRUTH TABLE** (X = Don't Care)

$\overline{E1}$	E2	$\overline{G}$	$\overline{W}$	Mode	V <sub>CC</sub> Current	Output	Cycle
H	X	X	X	Not Selected	I <sub>SB1</sub> , I <sub>SB2</sub>	High-Z	—
X	L	X	X	Not Selected	I <sub>SB1</sub> , I <sub>SB2</sub>	High-Z	—
L	H	H	H	Output Disabled	I <sub>CCA</sub>	High-Z	—
L	H	L	H	Read	I <sub>CCA</sub>	D <sub>out</sub>	Read Cycle
L	H	X	L	Write	I <sub>CCA</sub>	High-Z	Write Cycle

**ABSOLUTE MAXIMUM RATINGS** (See Note)

Rating	Symbol	Value	Unit
Power Supply Voltage	V <sub>CC</sub>	- 0.5 to 7.0	V
Voltage Relative to V <sub>SS</sub> (For Any Pin Except V <sub>CC</sub> )	V <sub>in</sub> , V <sub>out</sub>	- 0.5 to V <sub>CC</sub> + 0.5	V
Output Current	I <sub>out</sub>	± 30	mA
Power Dissipation	P <sub>D</sub>	2.0	W
Temperature Under Bias	T <sub>bias</sub>	- 10 to + 85	°C
Operating Temperature	T <sub>A</sub>	0 to + 70	°C
Storage Temperature — Plastic	T <sub>stg</sub>	- 55 to + 125	°C

NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPERATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high impedance circuit.

This BiCMOS memory circuit has been designed to meet the dc and ac specifications shown in the tables, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow of at least 500 linear feet per minute is maintained.

**DC OPERATING CONDITIONS AND CHARACTERISTICS**

(V<sub>CC</sub> = 5.0 V ± 10%, T<sub>A</sub> = 0 to + 70°C, Unless Otherwise Noted)

**RECOMMENDED OPERATING CONDITIONS**

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage (Operating Voltage Range)	V <sub>CC</sub>	4.5	5.0	5.5	V
Input High Voltage	V <sub>IH</sub>	2.2	—	V <sub>CC</sub> + 0.3*	V
Input Low Voltage	V <sub>IL</sub>	- 0.5**	—	0.8	V

\*V<sub>IH</sub> (max) = V<sub>CC</sub> + 0.3 V dc; V<sub>IH</sub> (max) = V<sub>CC</sub> + 2 V ac (pulse width ≤ 2.0 ns) or I ≤ 30 mA.

\*\*V<sub>IL</sub> (min) = - 0.5 V dc @ 30 mA; V<sub>IL</sub> (min) = - 2 V ac (pulse width ≤ 2 ns) or I ≤ 30 mA.

**DC CHARACTERISTICS**

Parameter	Symbol	Min	Max	Unit
Input Leakage Current (All Inputs, V <sub>in</sub> = 0 to V <sub>CC</sub> )	I <sub>lkg(I)</sub>	—	± 1	μA
Output Leakage Current ( $\overline{E1} = V_{IH}$ , or E2 = V <sub>IL</sub> , or $\overline{G} = V_{IH}$ , V <sub>out</sub> = 0 to V <sub>CC</sub> )	I <sub>lkg(O)</sub>	—	± 1	μA
Output High Voltage (I <sub>OH</sub> = - 4.0 mA)	V <sub>OH</sub>	2.4	—	V
Output Low Voltage (I <sub>OL</sub> = + 8.0 mA)	V <sub>OL</sub>	—	0.4	V

**POWER SUPPLY CURRENTS**

Parameter	Symbol	MCM6765A-8	MCM6765A-10	Unit
AC Active Supply Current (I <sub>out</sub> = 0 mA, V <sub>CC</sub> = Max, f = f <sub>max</sub> )	I <sub>CCA</sub>	185	175	mA
AC Standby Current ( $\overline{E1} = V_{IH}$ , or E2 = V <sub>IL</sub> , V <sub>CC</sub> = Max, f = f <sub>max</sub> )	I <sub>SB1</sub>	120	110	mA
CMOS Standby Current (V <sub>CC</sub> = Max, f = 0 MHz, $\overline{E1} \geq V_{CC} - 0.2$ V, or E2 ≤ V <sub>SS</sub> + 0.2 V, V <sub>in</sub> ≤ V <sub>SS</sub> , or V <sub>CC</sub> - 0.2 V)	I <sub>SB2</sub>	50	50	mA

**CAPACITANCE** ( $f = 1.0 \text{ MHz}$ ,  $dV = 3.0 \text{ V}$ ,  $T_A = 25^\circ\text{C}$ , Periodically Sampled Rather Than 100% Tested)

Characteristic	Symbol	Max	Unit
Address Input Capacitance	$C_{in}$	5	pF
Control Pin Input Capacitance ( $\overline{E1}$ , $E2$ , $\overline{G}$ , $\overline{W}$ )	$C_{in}$	6	pF
Input/Output Capacitance	$C_{I/O}$	6	pF

**AC OPERATING CONDITIONS AND CHARACTERISTICS**

( $V_{CC} = 5.0 \text{ V} \pm 10\%$ ,  $T_A = 0 \text{ to } +70^\circ\text{C}$ , Unless Otherwise Noted)

Input Timing Measurement Reference Level ..... 1.5 V      Output Timing Measurement Reference Level ..... 1.5 V  
 Input Pulse Levels ..... 0 to 3.0 V      Output Load ..... See Figure 1A  
 Input Rise/Fall Time ..... 3 ns

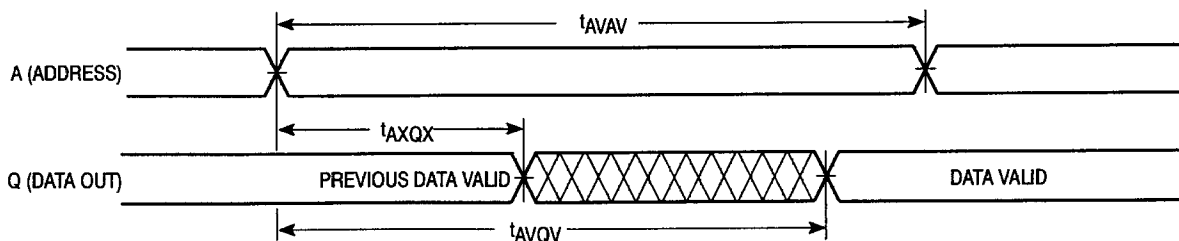
**READ CYCLE TIMING** (See Notes 1, 2, and 3)

Parameter	Symbol		MCM6765A-8		MCM6765A-10		Unit	Notes
	Standard	Alternate	Min	Max	Min	Max		
Read Cycle Time	$t_{AVAV}$	$t_{RC}$	8	—	10	—	ns	4
Address Access Time	$t_{AVQV}$	$t_{AA}$	—	8	—	10	ns	
Chip Enable Access Time	$t_{ELQV}$	$t_{ACS}$	—	8	—	10	ns	
Output Enable Access Time	$t_{GLQV}$	$t_{OE}$	—	4	—	5	ns	
Output Hold from Address Change	$t_{AXQX}$	$t_{OH}$	3	—	3	—	ns	
Chip Enable Low to Output Active	$t_{ELQX}$	$t_{LZ}$	1	—	1	—	ns	5, 6, 7
Chip Enable High to Output High-Z	$t_{EHQZ}$	$t_{HZ}$	0	4.5	0	5	ns	5, 6, 7
Output Enable Low to Output Active	$t_{GLQX}$	$t_{LZ}$	0	—	0	—	ns	5, 6, 7
Output Enable High to Output High-Z	$t_{GHQZ}$	$t_{HZ}$	0	4	0	5	ns	5, 6, 7

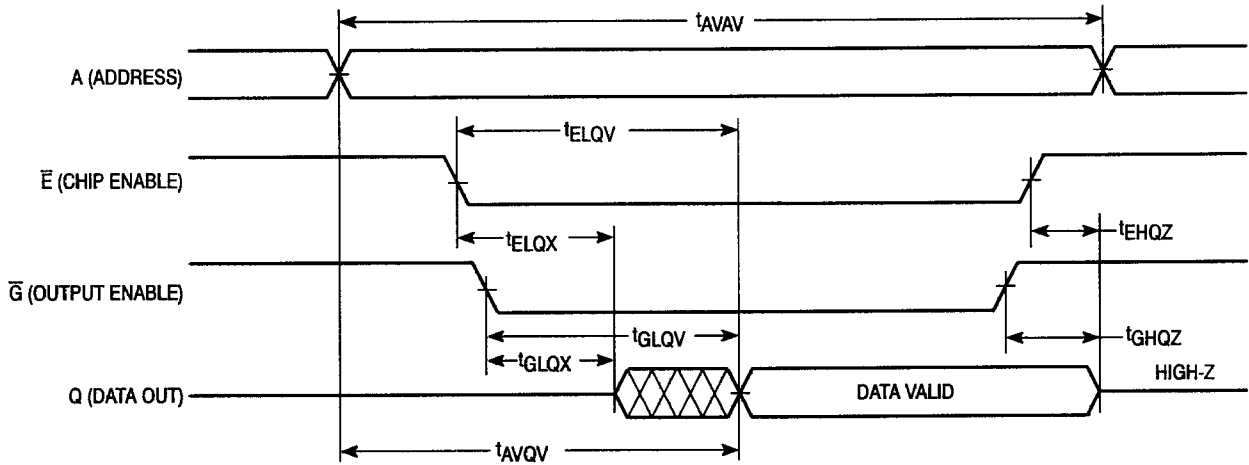
**NOTES:**

1.  $\overline{W}$  is high for read cycle.
2. Product sensitivities to noise require proper grounding and decoupling of power supplies as well as minimization or elimination of bus contention conditions during read and write cycles.
3.  $\overline{E1}$  is represented by E in this table. E2 would require a transition opposite of  $\overline{E1}$ .
4. All read cycle timings are referenced from the last valid address to the first transitioning address.
5. At any given voltage and temperature,  $t_{EHQZ\text{max}} < t_{ELQX\text{min}}$ , and  $t_{GHQZ\text{max}} < t_{GLQX\text{min}}$ , both for a given device and from device to device.
6. Transition is measured 200 mV from steady-state voltage with load of Figure 1B.
7. This parameter is sampled and not 100% tested.
8. Device is continuously selected ( $\overline{E1} = V_{IL}$ ,  $E2 = V_{IH}$ ,  $\overline{G} = V_{IL}$ ).
9. Addresses valid prior to or coincident with  $\overline{E}$  going low.

**READ CYCLE 1** (See Note 8)



### READ CYCLE 2 (See Note 9)



### AC TEST LOADS

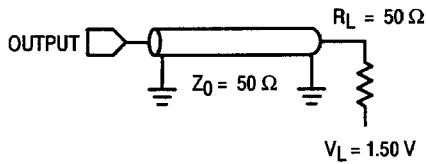


Figure 1A

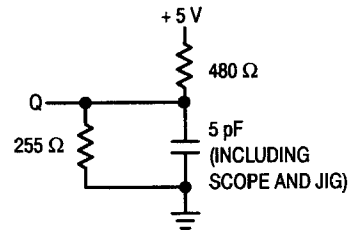


Figure 1B

### TIMING LIMITS

The table of timing values shows either a minimum or a maximum limit for each parameter. Input requirements are specified from the external system point of view. Thus, address setup time is shown as a minimum since the system must supply at least that much time (even though most devices do not require it). On the other hand, responses from the memory are specified from the device point of view. Thus, the access time is shown as a maximum since the module never provides data later than that time.

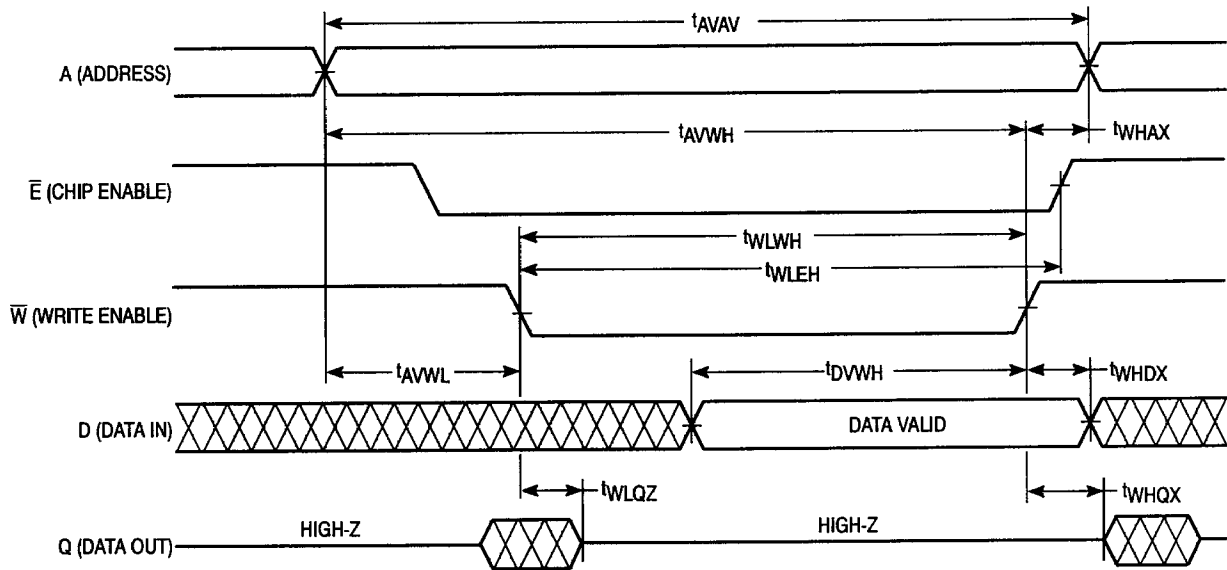
**WRITE CYCLE 1** ( $\bar{W}$  Controlled, See Notes 1, 2, and 3)

Parameter	Symbol		MCM6765A-8		MCM6765A-10		Unit	Notes
	Standard	Alternate	Min	Max	Min	Max		
Write Cycle Time	$t_{AVAV}$	$t_{WC}$	8	—	10	—	ns	4
Address Setup Time	$t_{AVWL}$	$t_{AS}$	0	—	0	—	ns	
Address Valid to End of Write	$t_{AVWH}$	$t_{AW}$	8	—	9	—	ns	
Write Pulse Width	$t_{WLWH}$ $t_{WLEH}$	$t_{WP}$	7	—	8	—	ns	
Data Valid to End of Write	$t_{DVWH}$	$t_{DW}$	4	—	5	—	ns	
Data Hold Time	$t_{WHDX}$	$t_{DH}$	0	—	0	—	ns	
Write Low to Data High-Z	$t_{WLQZ}$	$t_{WZ}$	0	4	0	5	ns	5,6,7
Write High to Output Active	$t_{WHQX}$	$t_{OW}$	3	—	3	—	ns	5,6,7
Write Recovery Time	$t_{WHAX}$	$t_{WR}$	0	—	0	—	ns	

**NOTES:**

1. A write occurs during the overlap of  $\bar{E}$  low and  $\bar{W}$  low.
2. Product sensitivities to noise require proper grounding and decoupling of power supplies as well as minimization or elimination of bus contention conditions during read and write cycles.
3.  $\bar{E}1$  is represented by E in this table. E2 would require a transition opposite of  $\bar{E}1$ .
4. All write cycle timing is referenced from the last valid address to the first transitioning address.
5. Transition is measured 200 mV from steady-state voltage with load of Figure 1B.
6. This parameter is sampled and not 100% tested.
7. At any given voltage and temperature,  $t_{WLQZ}$  max is less than  $t_{WHQX}$  min both for a given device and from device to device.

**WRITE CYCLE 1**



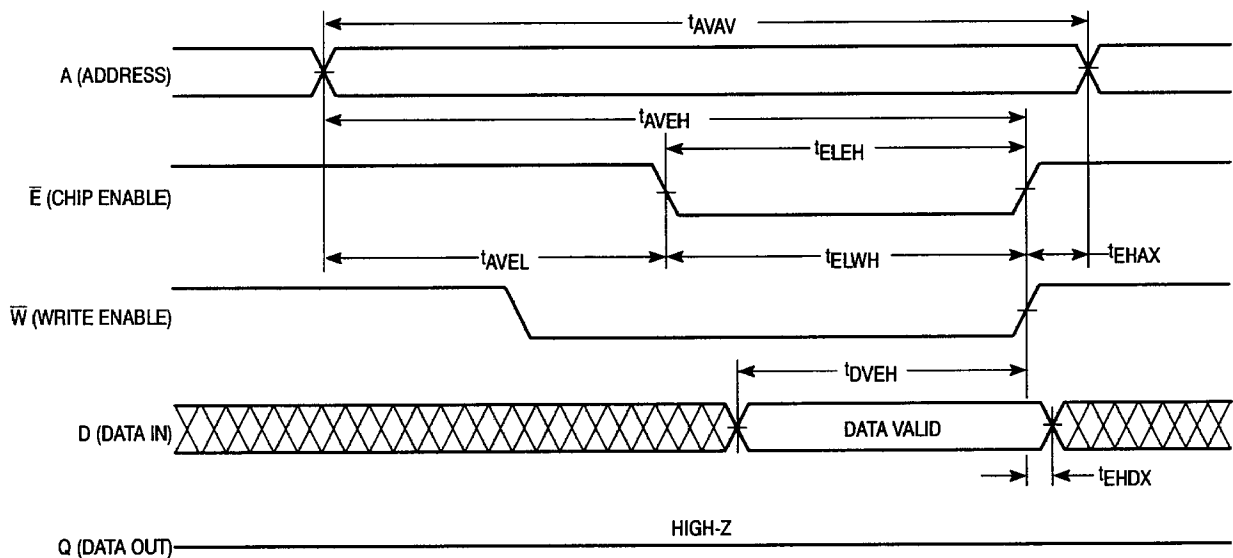
**WRITE CYCLE 2** ( $\bar{E}$  Controlled, See Notes 1, 2, and 3)

Parameter	Symbol		MCM6765A-8		MCM6765A-10		Unit	Notes
	Standard	Alternate	Min	Max	Min	Max		
Write Cycle Time	$t_{AVAV}$	$t_{WC}$	8	—	10	—	ns	4
Address Setup Time	$t_{AVEL}$	$t_{AS}$	0	—	0	—	ns	
Address Valid to End of Write	$t_{AVEH}$	$t_{AW}$	8	—	9	—	ns	
Chip Enable to End of Write	$t_{ELEH}$ , $t_{ELWH}$	$t_{CW}$	7	—	8	—	ns	5,6
Data Valid to End of Write	$t_{DVEH}$	$t_{DW}$	4	—	5	—	ns	
Data Hold Time	$t_{EHDX}$	$t_{DH}$	0	—	0	—	ns	
Write Recovery Time	$t_{EHAX}$	$t_{WR}$	0	—	0	—	ns	

**NOTES:**

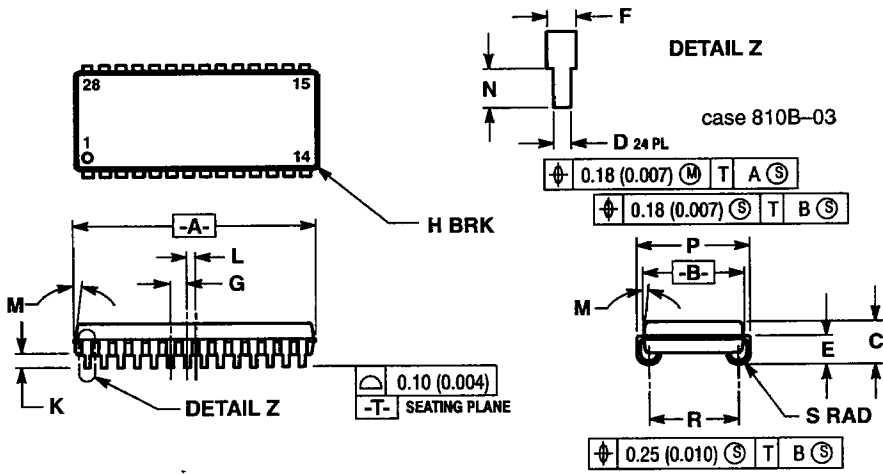
1. A write occurs during the overlap of  $\bar{E}$  low and  $\bar{W}$  low.
2. Product sensitivities to noise require proper grounding and decoupling of power supplies as well as minimization or elimination of bus contention conditions during read and write cycles.
3.  $\bar{E}1$  is represented by  $E$  in this table.  $E2$  would require a transition opposite of  $\bar{E}1$ .
4. All write cycle timing is referenced from the last valid address to the first transitioning address.
5. If  $\bar{E}$  goes low coincident with or after  $\bar{W}$  goes low, the output will remain in a high impedance condition.
6. If  $\bar{E}$  goes high coincident with or before  $\bar{W}$  goes high, the output will remain in a high impedance condition.

**WRITE CYCLE 2**



# PACKAGE DIMENSIONS

## J PACKAGE 300 MIL SOJ CASE 810B-03

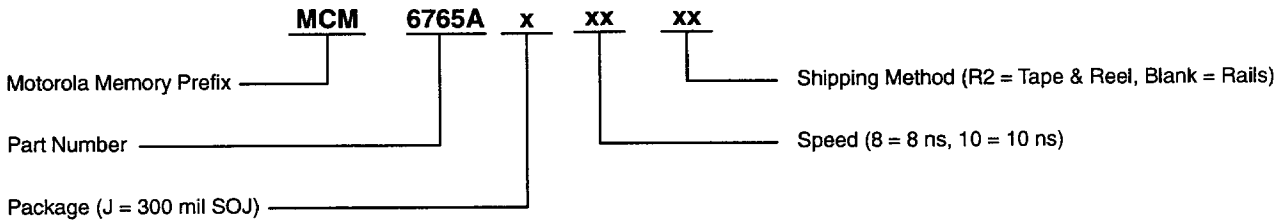


### NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. DIMENSION A & B DO NOT INCLUDE MOLD PROTRUSION. MOLD PROTRUSION SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
3. CONTROLLING DIMENSION: INCH.
4. DIM R TO BE DETERMINED AT DATUM -T.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	18.29	18.54	0.720	0.730
B	7.50	7.74	0.295	0.305
C	3.26	3.75	0.128	0.148
D	0.39	0.50	0.015	0.020
E	2.24	2.48	0.088	0.098
F	0.67	0.81	0.026	0.032
G	1.27 BSC		0.050 BSC	
H	0.50		0.020	
K	0.89	1.14	0.035	0.045
L	0.64 BSC		0.025 BSC	
M	0°	10°	0°	10°
N	0.76	1.14	0.030	0.045
P	8.38	8.64	0.330	0.340
R	6.60	6.86	0.260	0.270
S	0.77	1.01	0.030	0.040

## ORDERING INFORMATION (Order by Full Part Number)



Full Part Numbers — MCM6765AJ8      MCM6765AJ8R2  
    MCM6765AJ10      MCM6765AJ10R2